


### Mitigation of inter-cell coupling effects in NAND flash memory (Technion)

**code:** COM-1282

NAND flash memory is a popular data storage facility at various electronic devices. However, it suffers from an inter-cell coupling effect which reduces the memory functionality. An innovative method improves the NAND flash memory operations by diminish the inter-cell coupling effect.

#### Contact for more information:

T3 Team , +972-4-8294853

---

T - Technion Technology Transfer  
Technion City, Senate Bldg., Haifa 32000, Israel  
Tel. 972-4-829-4851; 972-8325-375  
Fax. 972-4-832-0845